



Journée Thématique "Microscopie " Grenoble 22 mars 2016

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| 9h -9h10 | Accueil Minatec | |
| 9h10-9h20 | Introduction | Catherine Bougerol (Institut Néel) |
| 9h20-9h45 | Quantification du signal HAADF : Composition et déformation à l'échelle atomique | Konstantinos Panzas (LPN) |
| 9h45-10h10 | Chemical quantification by EDX in TEM and SEM | Eric Robin (INAC) |
| 10h10-10h55 | Mesure de dopants par sonde atomique tomographique | Lynda Amichi (INAC) |
| 10h55-11h15 | Pause | |
| 11h15-11h40 | Traitement SiN pour le contrôle de la croissance de GaN : études TEM à mener | Philippe Vénégues (CRHEA) |
| 11h40-12h05 | Polarité et croissance MBE des nanofils GaN | Ludovic Largeau (LPN) |
| 12h05-12h30 | Mechanisms of polarity inversion during the MOCVD growth of III-nitrides on sapphire investigated by HRTEM | Natalia Stolyarchuk (CRHEA) |
| 12h30-14h | Repas | |
| 14h-14h25 | Polarity determination from ABF and Differential Phase Contrast | Bénédict Haas (INAC) |
| 14h25-14h50 | Electron Diffraction for polarity and Strain Measurement | Jean-Luc Rouvière (INAC) |
| 15h-17h | Questions, Discussions | |